

L Number	Hits	Search Text	DB	Time stamp
1	200	wafer and in-line and yield and prediction	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/01 12:18
2	16493	wafer and yield and analysis	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/01 12:19
3	2711	(wafer and yield and analysis) and statistical	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/01 12:19
4	665	((wafer and yield and analysis) and statistical) and regression	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/01 12:19
5	601	((((wafer and yield and analysis) and statistical) and regression) and sample	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/01 12:20
6	409	(((((wafer and yield and analysis) and statistical) and regression) and sample) and parameter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/01 12:20
-	16	702/84.ccls. and database and test and correlation	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 13:19
-	9	702/84.ccls. and database and test and analyze and correlation and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/27 09:56
-	100	700/109.ccls. and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 13:58
-	669	wafer and (quality near control) and analyzing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 14:00
-	108	(wafer and (quality near control) and analyzing) and parameter and lot and sample	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 14:19
-	9	(quality adj control) same test same parameter same analyzing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 14:29

-	505	((quality adj control) and sample and parameter and search and database and analyzing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 14:31
-	40	((quality adj control) and sample and parameter and search and database and analyzing) and correlating and predicting	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 14:32
-	113	((quality adj control) and sample and parameter and search and database and analyzing) and correlating	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 14:37
-	31	((quality adj control) and sample and parameter and search and database and analyzing) and (((quality adj control) and sample and parameter and search and database and analyzing) and correlating) and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 15:15